



## Description

- Advanced Trench MOS Technology
- Low Gate Charge
- Low  $R_{DS(ON)}$
- 100% EAS Guaranteed
- Green Device Available

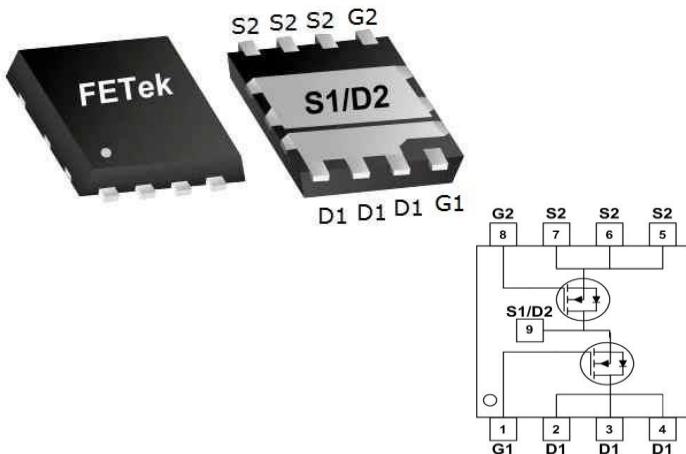
## Product Summary

BVDSS	RDSON	ID
30V	5.2mΩ	50A
30V	3.9mΩ	60A

## Applications

- Power Management in Desktop Computer or DC/DC Converters.
- Isolated DC/DC Converters in Telecom and Industrial.

## PRPAK5X6 Pin Configuration



## Absolute Maximum Ratings

Symbol	Parameter	Rating		Units
		Die1	Die2	
$V_{DS}$	Drain-Source Voltage	30	30	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	$\pm 20$	V
$I_D @ T_c = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	50	60	A
$I_D @ T_c = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	31	38	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	100	120	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	61.3	80	mJ
$I_{AS}$	Avalanche Current	35	40	A
$P_D @ T_c = 25^\circ C$	Total Power Dissipation <sup>4</sup>	21	22	W
$T_{STG}$	Storage Temperature Range	-55 to 150	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Typ. D1	Typ. D2	Max. D1	Max. D2	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	50	50	65	65	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	4.6	4.4	6	5.8	°C/W

Die1 N-Channel Electrical Characteristics ( $T_J=25^\circ C$ , unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	30	---	---	V
$R_{DS(ON)}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=10V, I_D=20A$	---	4.5	5.2	$m\Omega$
		$V_{GS}=4.5V, I_D=15A$	---	7.2	9	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	1.2	1.7	2.2	V
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=30V, V_{GS}=0V, T_J=25^\circ C$	---	---	1	$\mu A$
		$V_{DS}=30V, V_{GS}=0V, T_J=55^\circ C$	---	---	5	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	$\pm 100$	nA
$g_{fs}$	Forward Transconductance	$V_{DS}=5V, I_D=20A$	---	65	---	S
$R_g$	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1MHz$	0.8	1.7	2.6	$\Omega$
$Q_g$	Total Gate Charge (4.5V)	$V_{DS}=15V, V_{GS}=10V, I_D=20A$	---	9	---	$nC$
$Q_{gs}$	Gate-Source Charge		---	2.8	---	
$Q_{gd}$	Gate-Drain Charge		---	3.6	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=15V, V_{GS}=10V, R_G=3\Omega$ $I_D=20A$	---	7	---	$ns$
$T_r$	Rise Time		---	18.8	---	
$T_{d(off)}$	Turn-Off Delay Time		---	19.5	---	
$T_f$	Fall Time		---	3.4	---	
$C_{iss}$	Input Capacitance	$V_{DS}=15V, V_{GS}=0V, f=1MHz$	---	1113	---	$pF$
$C_{oss}$	Output Capacitance		---	436	---	
$C_{rss}$	Reverse Transfer Capacitance		---	55	---	

## Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$I_s$	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0V$ , Force Current	---	---	20	A
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0V, I_s=1A, T_J=25^\circ C$	---	---	1	V

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is  $V_{DD}=25V, V_{GS}=10V, L=0.1mH, I_{AS}=35A$
- 4.The power dissipation is limited by  $150^\circ C$  junction temperature
- 5.The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

Die2 N-Channel Electrical Characteristics ( $T_J=25\text{ }^{\circ}\text{C}$ , unless otherwise noted)

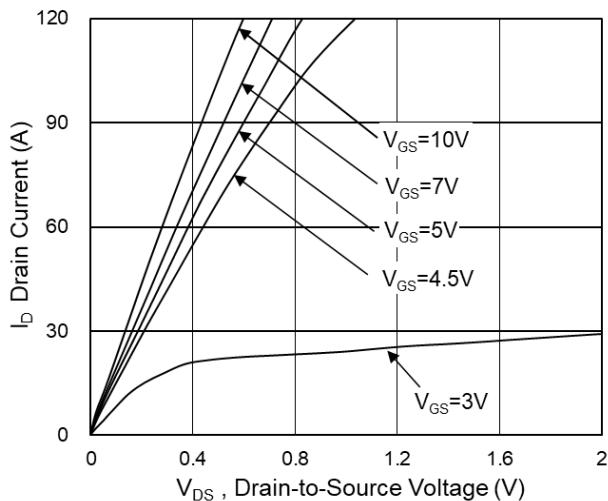
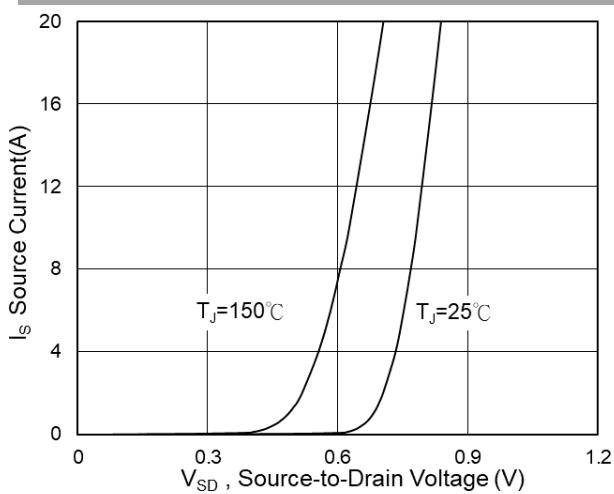
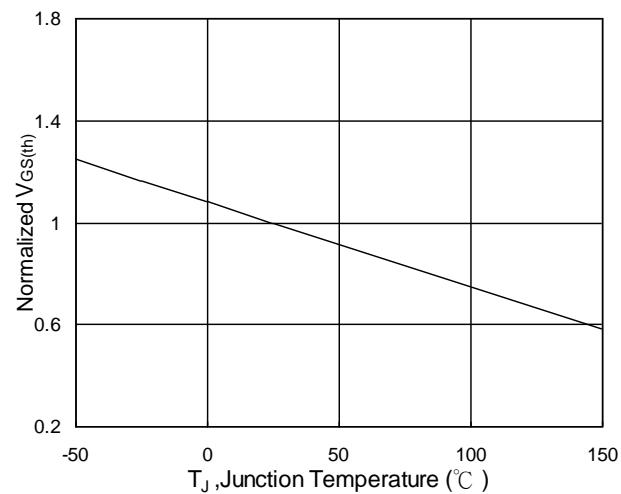
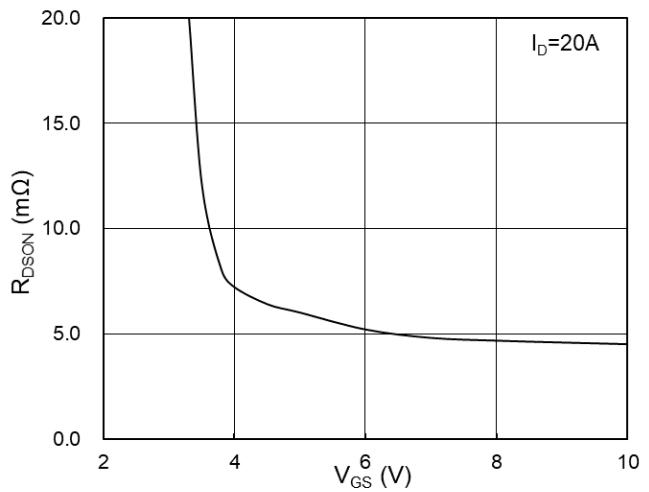
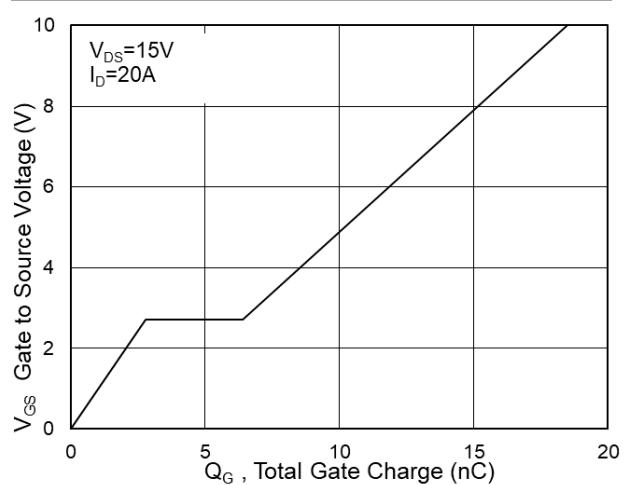
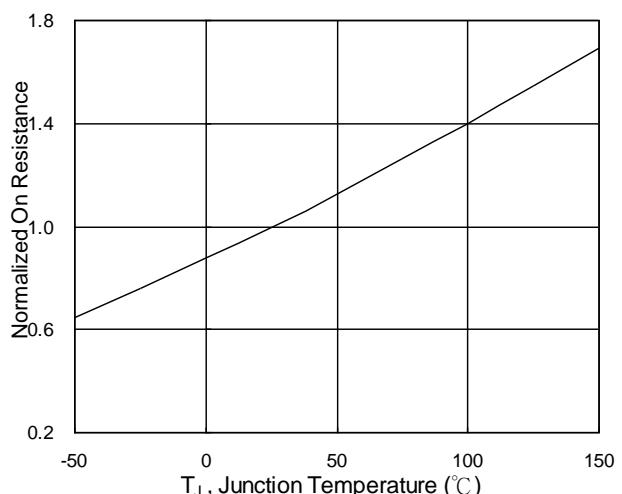
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$	30	---	---	V
$R_{DS(ON)}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=10\text{V}$ , $I_D=20\text{A}$	---	3.2	3.9	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$ , $I_D=15\text{A}$	---	4.9	6.1	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=250\mu\text{A}$	1.2	1.7	2.2	V
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=30\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=25\text{ }^{\circ}\text{C}$	---	---	1	$\text{uA}$
		$V_{DS}=30\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=55\text{ }^{\circ}\text{C}$	---	---	5	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS}=\pm 20\text{V}$ , $V_{DS}=0\text{V}$	---	---	$\pm 100$	nA
$g_{fs}$	Forward Transconductance	$V_{DS}=5\text{V}$ , $I_D=20\text{A}$	---	75	---	S
$R_g$	Gate Resistance	$V_{DS}=0\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	0.7	1.65	2.6	$\Omega$
$Q_g$	Total Gate Charge (4.5V)	$V_{DS}=15\text{V}$ , $V_{GS}=4.5\text{V}$ , $I_D=20\text{A}$	---	14.7	---	$\text{nC}$
$Q_{gs}$	Gate-Source Charge		---	5.8	---	
$Q_{gd}$	Gate-Drain Charge		---	3.5	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=15\text{V}$ , $V_{GS}=10\text{V}$ , $R_G=3\Omega$ $I_D=20\text{A}$	---	7.5	---	$\text{ns}$
$T_r$	Rise Time		---	20.2	---	
$T_{d(off)}$	Turn-Off Delay Time		---	21.6	---	
$T_f$	Fall Time		---	4.4	---	
$C_{iss}$	Input Capacitance	$V_{DS}=15\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	1476	---	$\text{pF}$
$C_{oss}$	Output Capacitance		---	556	---	
$C_{rss}$	Reverse Transfer Capacitance		---	70	---	

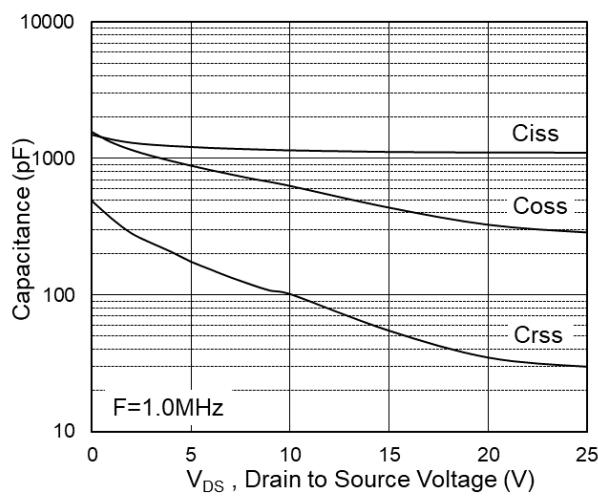
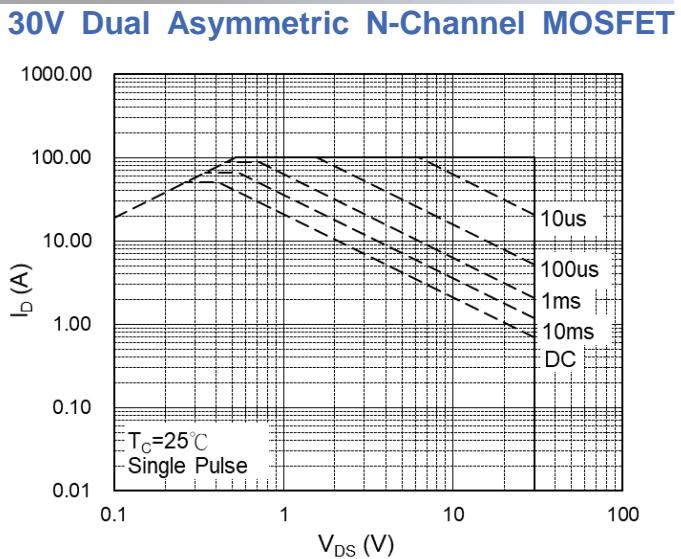
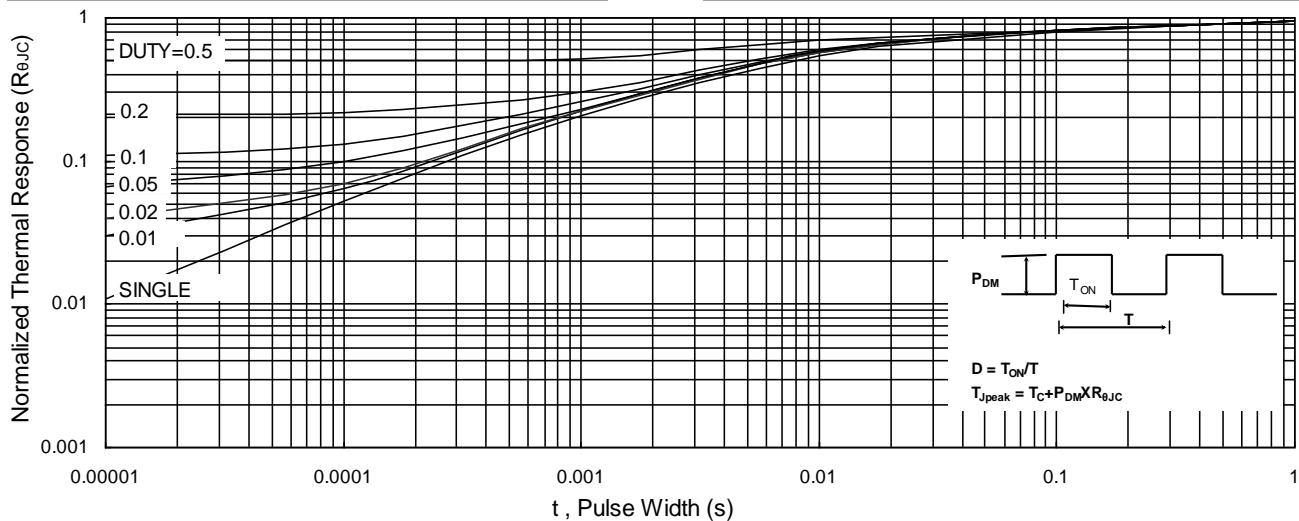
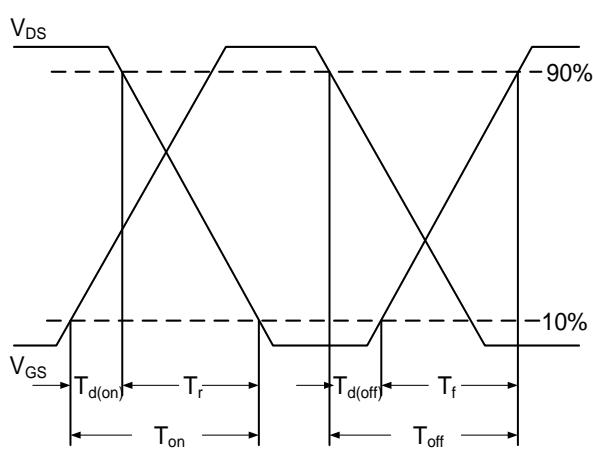
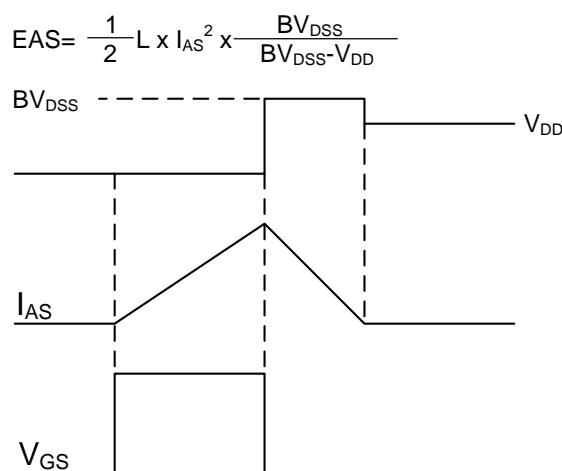
## Diode Characteristics

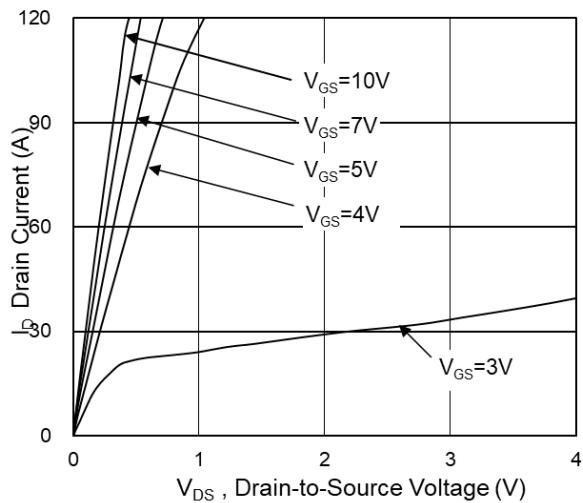
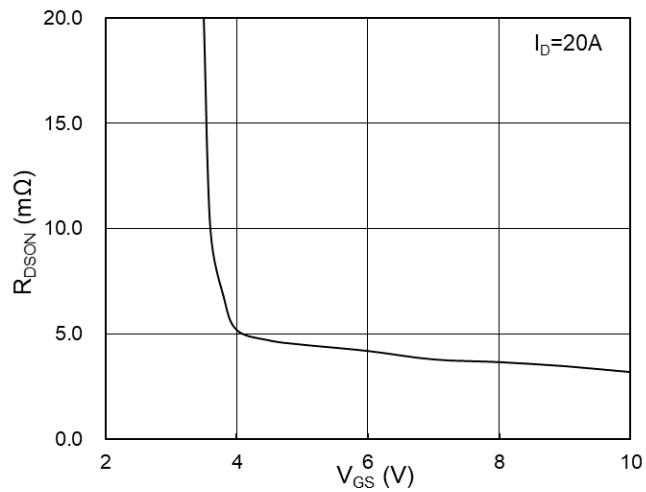
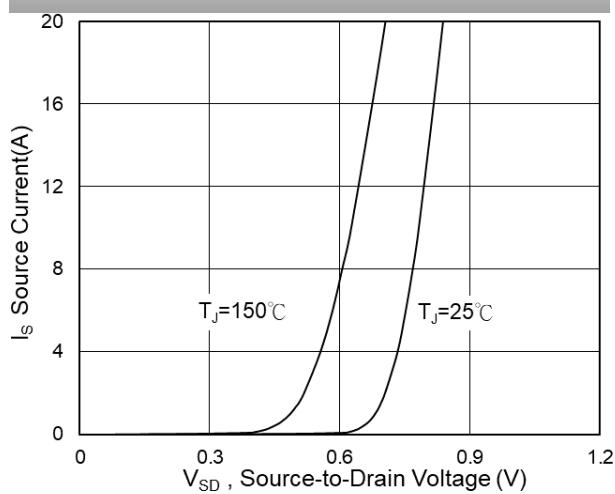
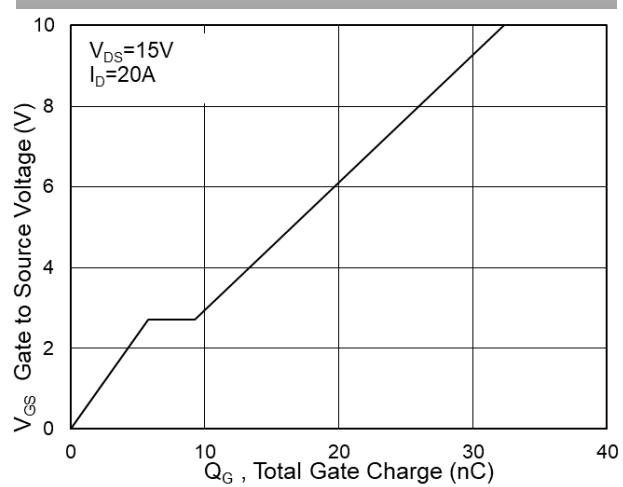
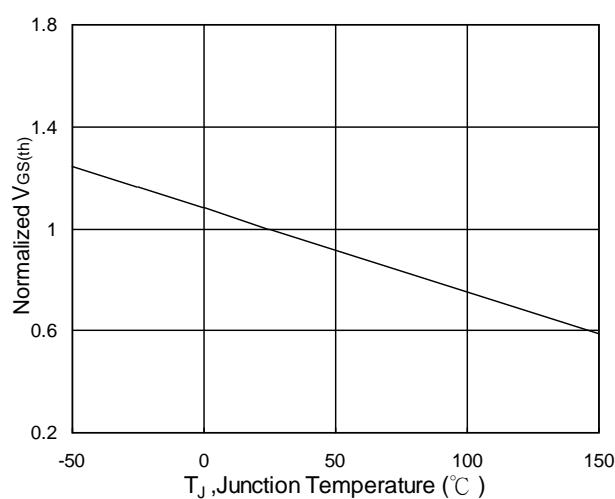
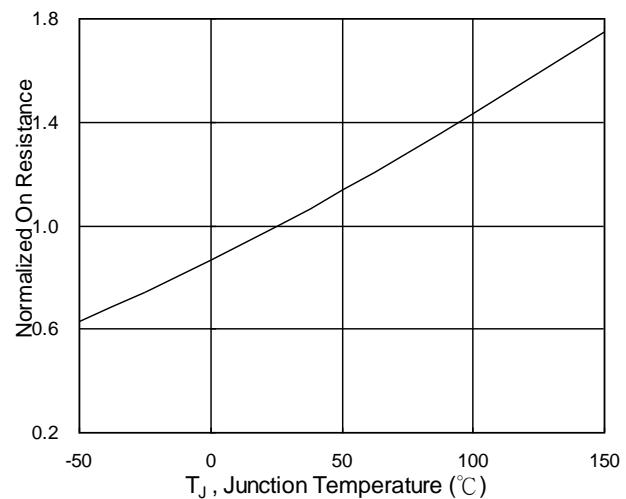
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$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0\text{V}$ , $I_s=1\text{A}$ , $T_J=25\text{ }^{\circ}\text{C}$	---	---	1	V

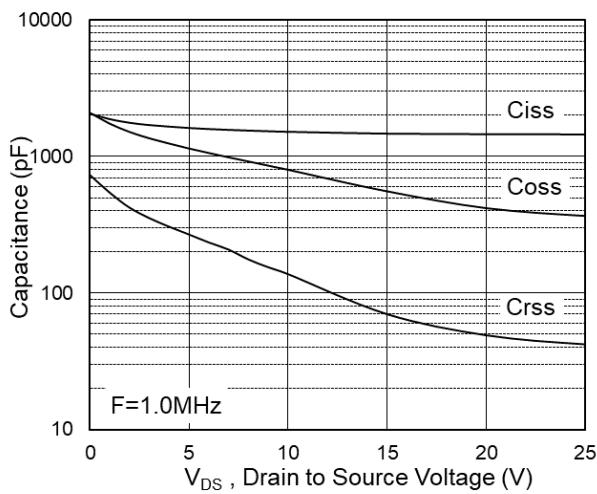
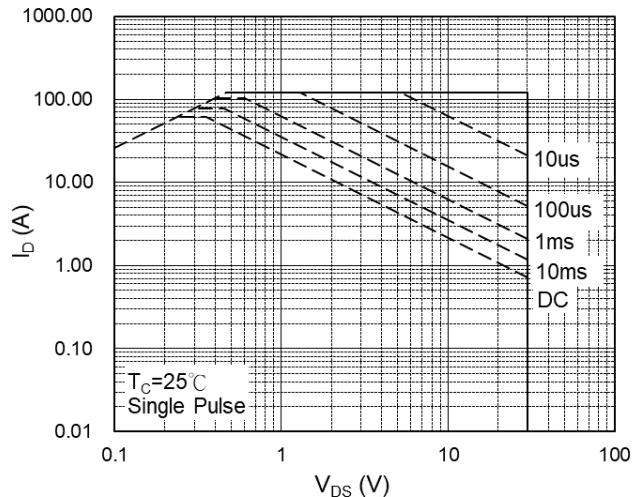
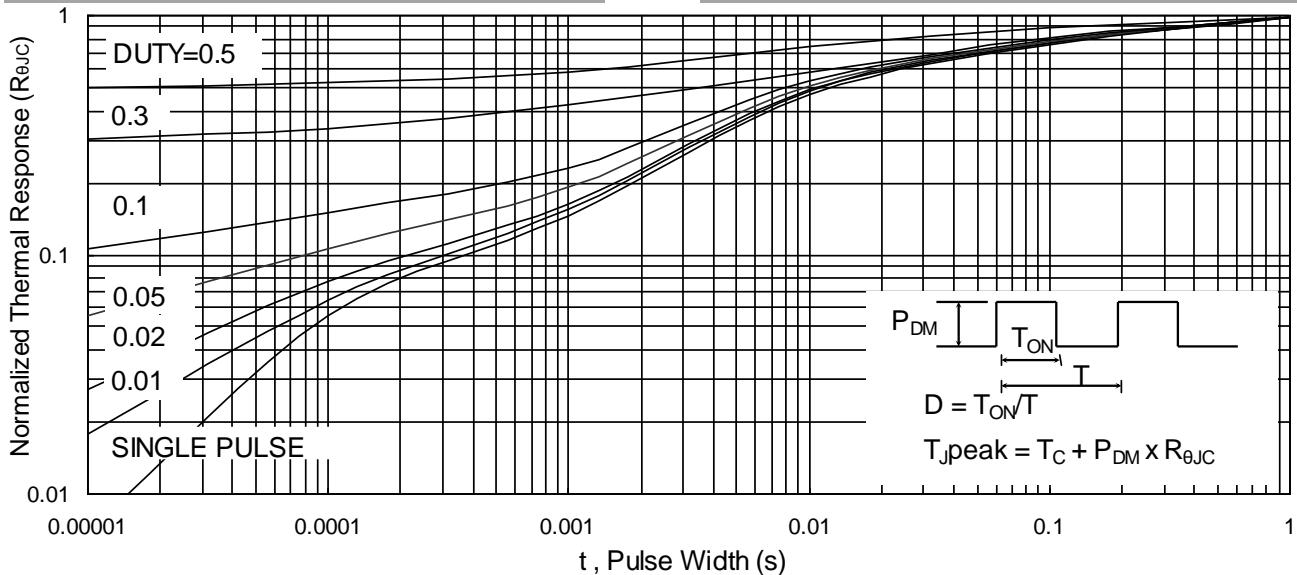
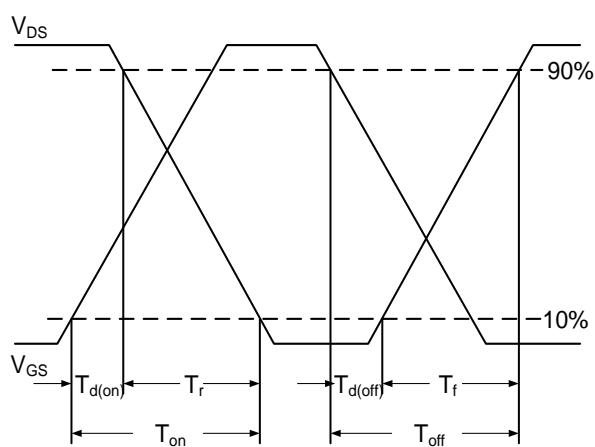
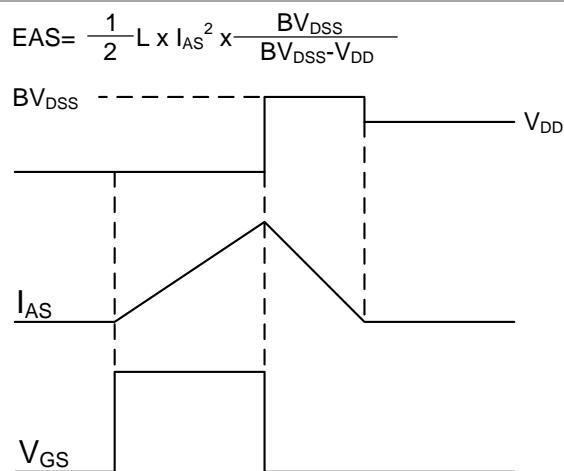
Note :

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- 4.The power dissipation is limited by  $150\text{ }^{\circ}\text{C}$  junction temperature
- 5.The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

**N- Channel Typical Characteristics (Die1)**

**Fig.1 Typical Output Characteristics**

**Fig.3 Source Drain Forward Characteristics**

**Fig.5 Normalized  $V_{GS(th)}$  vs  $T_J$** 

**Fig.2 On-Resistance vs G-S Voltage**

**Fig.4 Gate-Charge Characteristics**

**Fig.6 Normalized  $R_{DS(on)}$  vs  $T_J$**


**Fig.7 Capacitance**

**Fig.8 Safe Operating Area**

**Fig.9 Normalized Maximum Transient Thermal Impedance**

**Fig.10 Switching Time Waveform**

**Fig.11 Unclamped Inductive Switching Waveform**

**N-Channel Typical Characteristics (Die2)**

**Fig.1 Typical Output Characteristics**

**Fig.2 On-Resistance vs G-S Voltage**

**Fig.3 Source Drain Forward Characteristics**

**Fig.4 Gate-Charge Characteristics**

**Fig.5 Normalized  $V_{GS(th)}$  vs  $T_J$** 

**Fig.6 Normalized  $R_{DS(on)}$  vs  $T_J$**


**Fig.7 Capacitance**

**Fig.8 Safe Operating Area**

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